PRODUCTION CONTROL MATERIAL RECEIPT

Critical raw materials received.

QUALITY CONTROL GATE – INCOMING INSPECTION

Raw materials inspected against DS-IMP procurement specifications.

WAFER FABRICATION

Raw wafers are processed through diffusion, photolithography, implant, thin films, and etch. All areas use SPC to control the process.

QUALITY CONTROL DURING WAFER FABRICATION

- A) Critical Dimensions
- B) Oxide Thickness
- C) Thin Film Thickness
- D) Sheet Resistivity
- E) Reflectivity
- F) CV Drift
- G) Mask Alignment
- H) Particles
- I) Etch Completion
- J) Visual Defects

QUALITY CONTROL GATE – WAFER ACCEPTANCE

- A) Visual Each wafer is visually inspected under a microscope for defects, mask alignment, and mask sequence.
- B) Parametric Test Five specially designed test sites on each wafer are tested for process and product parameters to verify processing integrity.

100% DIE ELECTRICAL TEST

All die are either 100% or sampled at electrical sort and tested for functionality and parameter conformance to wafer sort limits. Yields used for process, design, and test analysis.



QUALITY CONTROL MONITOR – DIE ELECTRICAL TEST

Visual Inspection for:

- A) Process Defects
- B) Probe Scratches or Other Damage
- C) Electrical Test Anomalies
- D) Correct Probe Marks

SHIP WAFERS TO ASSEMBLY

100% WAFER SAW

100% Saw through and clean.

QUALITY CONTROL MONITOR – SAW

- A) RI Wafer Resistivity
- B) Kerf Width
- C) Chips and Cracks

Criteria:

- A) Misscribed Die
- **B)** Scratches
- C) Smooth Cut

QUALITY CONTROL GATE – OPTICAL INSPECTION

Per MIL-STD 883C Method 2010.8 Condition B LTPD = 5%

DIE MOUNT

QUALITY CONTROL MONITOR – DIE MOUNT INSPECTION

Die adhesion test by subcontracted assembler. Visual inspection (4 dice 1X/ Machine/ Shift, 20 units, Acc = 0, Rej = 1)

Criteria:

- A) Scratches, Cracks on Die
- B) Die Placement, Orientation
- C) Stray Epoxy



DIE MOUNT CURE

175 ± 6°C /1Hr.

LEAD BONDING

QUALITY CONTROL GATE – LEAD BONDING

LTPD = 5%

QUALITY CONTROL GATE – LEAD BOND INSPECTION

Bond Strength tested once per shift. Minimum grams for 1.3 mil. = 3 grams.

QUALITY CONTROL GATE – 3RD OPTICAL INSPECTION

Per MIL-STD 883C Method 2010.8 Condition B LTPD = 5%

Criteria:

- A) Missing Die
- **B)** Missing Wires
- C) Poor Lead Dress

D) Conductive Contamination

MOLD

Post Mold Cure $- 175 \pm 5^{\circ}C/6$ Hr.

QUALITY CONTROL MONITOR – MOLD

(4X/Shift, 20 units, Acc = 0, Rej = 1)

Criteria:

A) Deflash

- B) Package Voids
- C) Bubbles, Blisters

TRIM & FORM LEADS





Criteria:

A) Missing Plating

B) Extraneous Solder

C) Flaking, Peeling

QUALITY CONTROL GATE – SOLDER THICKNESS

X-ray fluroderm on 12points/package/machine/shift, from 2 strips The pure tin thickness=400 microinch minimum

QUALITY CONTROL MONITOR – SOLDERABILTY

Per MIL-STD 883C Method 2003 - 6 units

Criteria:

- A) 100% Coverage on Functional Area of Lead
- B) Solder Bridging, Lump, Ball
- C) Contamination

MARK

QUALITY CONTROL MONITOR – MARK

(4X/Shift, 20 units, Acc = 0, Rej = 1)



Criteria:

A) Illegible Marking

B) Incomplete Marking

C) Marking Placement

MARK CURE

160 ± 5°C/ 1Hr.

QUALITY CONTROL MONITOR – MARK PERMANENCY

Per MIL-STD 883C Method 2015 (2X/Shift, 22 units, Acc = 0, Rej = 1)

PRODUCTION FINAL TEST (25°C)

Every unit tested for conformance to all guaranteed datasheet parameters.

QUALITY CONTROL GATE – ELECTRICAL TEST (25°C)

A sample is pulled per MIL-STD 105D to guarantee an outgoing electrical AQL of 0.1% for guaranteed electrical parameters.

PRODUCTION FINAL VISUAL INSPECTION

Every unit checked for correct marking, orientation, and any package defects obtained during assembly, test, or production conditioning.

QUALITY CONTROL GATE – FV INSPECTION

A sample is pulled per MIL-STD 105D to guarantee an AQL of 0.1% for visually rejectable defects.

PRODUCTION PRODUCT LABELING & PACKAGING

SHIP TO DS-IMP

QUALITY CONTROL MONITOR – INCOMING INSPECTION



Criteria:

- A) Labeling and Device Marking Correct
- B) Packaging
- C) Quantities Correct

QUALITY CONTROL GATE – LOT ACCEPTANCE INTO FINISHED GOOD STORES

Each sublot examined by QA to verify conformance to standards.

FINISHED GOOD STORES

Product stored with finished goods disposition form attached detailing the product's store classification.

SHIPPING PREPARATION

Product packaged using approved anti-static and Faraday shielding materials.

QUALITY CONTROL GATE – SHIPPING

Criteria:

A) Labeling Correct

B) Packaging and Preparation for Shipment Correct

C)Quantities Correct

SHIPMENT

